

Supplemental Document

References

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- [2] Kim et al., *Adv. Funct. Mater.* 30.21 (2020): 1910214.
- [3] Gao et al., *Adv. Opt. Mater.* 6.9 (2018): 1700829.
- [4] Lee et al., *Thin Solid Films* 693.1 (2020): 137672

Figure

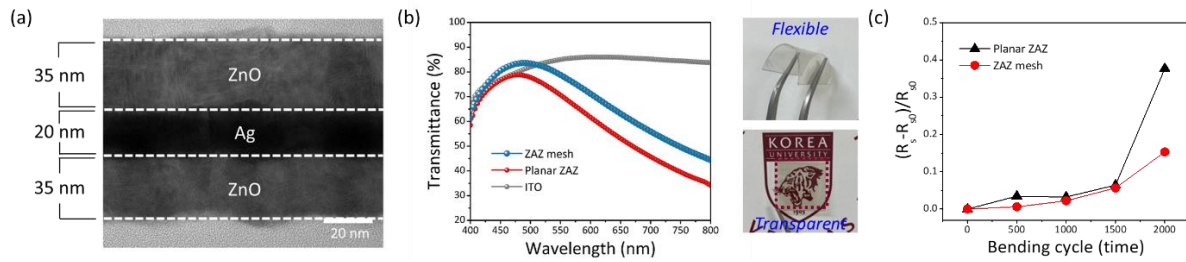


Figure 1. (a) Cross-sectional TEM images of ZAZ mesh electrode (b) Transmittance spectra of ZAZ mesh electrode, planar ZAZ and ITO (c) Bending radius-dependent sheet resistance variation. ΔR_s and R_{s0} represent “ R_s (after bending test) minus R_{s0} (before bending test)” and “ R_{s0} (before bending test)”, respectively.